Generic studies for industrial heat exchanger fouling

Development of a Pilot-monitor

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Summary

As part of the European CEC Project Joue-0040-C 'Generic Studies for Industrial Heat Exchanger Fouling' a study was undertaken to develop a gas-side fouling pilot monitor.

The monitor device is designed to provide an indication of the progress of fouling within a heat exchanger. The increase of the temperature and the change of the emission coefficient of the heat exchanger surfaces indicate fouling.

The measuring principle for the monitor is the measurement of infra-red radiation emitted from the fouled surface of a heat exchanger at three or more wavelengths. The temperature and the emissivity of the fouled surface are computed by iterative fitting of the Planck equations.

A camera set-up is selected. This presents the possibility of obtaining images of streaks of the surface, thus measuring the temperature and the emissivities at different locations on a fouled heat exchanger pipe.

A laboratory test facility is set up in order to test the principle of the monitor. The aim of the laboratory tests is to verify the surface temperatures and the emission coefficients measured and calculated by the monitor.

The results of the laboratory tests showed that the temperatures calculated by the software differ in some cases by more than 10 °C from the temperature measured by a thermocouple and that the emission coefficient in some cases differs by more than 10 % from the real emission coefficient. These large differences are probably caused by the relatively large fluctuations in the measured data. Expectations are that improvement in the stability of the measuring method will improve the quality of the input data of the iteration program. This will probably result in a more exact calculation of the surface temperatures and emission coefficients.

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1 Objective

The objective of this study is to develop a measuring method suitable for monitoring the gas-side fouling of industrial heat exchangers.

A measuring method was chosen which is based on the measurement of infrared radiation emitted from a fouled surface. It is possible to determine the temperature and emissivity of a heat exchanger surface with the data of emitted radiation.

A laboratory test facility is set up. With the laboratory tests we aim to verify the surface temperatures and the emission coefficients measured and calculated by the monitor. The surface temperature is therefore also measured by a thermocouple. The emission coefficient is determined separately by two infrared cameras.

2 Introduction

In general fouling is the main cause of diminishing efficiency of a heat exchanger and can therefore also result in economic loss.

The project "Generic studies for industrial heat exchanger fouling", contract JOUE - 0040 - C, has as its main objective the development, construction and validation of mathematical models which may be used to predict the extent of gas-side heat exchanger fouling for a variety of environments. In addition a practical fouling monitor has been designed. This monitor in combination with the mathematical models enables the user to judge the fouling of the surface.

The monitor device is designed to give an indication of the progress of fouling within a heat exchanger. The increase in the temperature and the change of the emission coefficient of the heat exchanger surface indicate fouling. An optical, infrared principle is selected as the most suitable measuring principle because it can measure temperatures without contact.

The monitor measures the infrared radiation emitted by a heat exchanger surface and calculates the temperature and emissivity.

The project is divided into two parts. The first part of the investigation covers the development of the method and the design of the camera. The selection of the measuring principle and the theoretical background of the principle are described in chapter 5.1 and 5.2. The practical design of the monitor, covering the selection of the infrared detector and the choice of the filters, is described in 5.3. The software needed to calculate the temperatures and the emission coefficients from the measured radiation is also described in chapter 5.3.

The second part of the investigation covers the testing and verification of the monitor. For this purpose a laboratory test facility is set up. The experimental test set-ups and the measuring equipment are described in chapter 5.4.

Experiments have been done on one test tube. Results of these experiments are described in chapter 6.

3 Conclusions

A method for the monitoring of gas-side fouling based on infrared emission of heat exchanger surfaces has been developed. A monitor based on this method for the measurement of surface temperatures and emissivities has been designed and built. The temperature and emissivity are calculated from Planck's equation through iteration with the aid of a computer.

The monitor is still too vulnerable to be used under industrial conditions. The monitor has to be shielded from dust, water and aggressive components.

The results of the tests with the monitor showed that the response of the monitor is not constant in time and that the measuring data exhibit rather large fluctuations.

The results of the laboratory tests showed that the temperatures calculated by the software differ in some cases by more than 10 °C from the temperature measured by a thermocouple and that the emission coefficient in some cases differs by more than 10 % from the real emission coefficient. These large differences are probably caused by the relatively large fluctuations in the measured data.

4 Table of symbols

В	= the measured radiation energy	$[W/m^2]$
h	= Planck's constant	[Js]
С	= speed of light	[m/s]
k	= Boltzmann's constant	[J/K]
n	= number of experiments	[-]
r	= transmission	[-]
T_{o}	= surface temperature	[K]
T_{e}	= environment temperature	[K]
Q	= intensity of radiation	$[W/m^2]$
3	= emission coefficient	[-]
λ	= wavelength	[m]
σ	= Stefan-Boltzmann's constant	$\left[W/m^2K^4\right]$

5 The fouling monitor

5.1 Selection of the measuring principle

At the start of the project for the development of a pilot monitor for gas-side fouling of heat exchangers, it had to be established which type of detection system should be considered for further research.

A number of criteria played an important role. A direct contact with the surface under examination must be avoided as far as possible. Besides that the monitor must be flexible because in general the gas-side surfaces of a heat exchanger are not easily accessible. The system must also not be too vulnerable because the monitor will often be used in aggressive environments.

Based on these considerations, non-contact methods like acoustic or optical detection systems are logical options.

The registration and/or generation of vibrations on surfaces of industrial heat exchangers is not likely to be easy. Gas and coolant streams of changing temperatures and the breaking off of pieces of fouling are potential important sources of interference for acoustic methods. Furthermore a solid contact must be made with the surface under examination for the registration of vibrations.

It was therefore decided to concentrate the research primarily on an optical system. Optical methods for the measurement of layer thickness, for example ellipsometry, have however not been considered because of the expected thickness and roughness of the layers. Thicknesses of several centimetres, the diversity of the fouling, from porous coal to cement-like materials and in some cases stalactites of many kilos, make reflective measurement of layer thicknesses impossible.

Deliberations with and earlier reports from the partners in the Joule project showed that there is a connection between the temperature distribution over the surface and the fouling of a heat exchanger. This can easily be explained by Figure 1. Figure 1^a shows a drawing of a clean heat exchanger pipe and figure 1^b shows a fouled heat exchanger pipe. The cold medium is inside the pipe and the hot medium (gas) is outside the tube. The temperature profile through the tube-wall can be drawn for both situations. In the figure it can easily be seen that a fouling layer results in a higher surface temperature. The fouling layer on the tube works like an isolating layer.

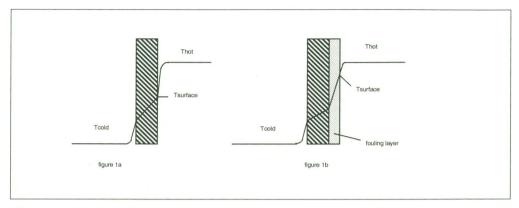


Figure 1 Influence of fouling on the surface temperature

The temperature of a surface is optically measurable by using the infra-red emission. Potential problems with this technique are the reflection of radiation by the surface under examination and the variable emissivity.

In addition the (changing) emission coefficient might give information on the nature of the fouling.

These considerations were the reason for concentrating efforts on the development of an image forming system for the registration of surface temperature and emissivity. This system uses a technique which is based on multi-wavelengths infra-red emission measurement.

5.2 Theoretical background

A literature search produced a number of articles in which infrared detection systems are described. The most useful was that of Tank and Dietl of the German "Institut für Optoelektronik" (1). It describes a method for the temperature measurement of highly reflective surfaces (patented in 1989).

The infrared radiation from a grey surface is determined by three parameters: surface temperature, environment radiation and emission coefficient. The principle of the technique described is the measurement of infrared energy at different wavelengths (theoretically at least three). After these measurements the three parameters can be determined from Planck's equations, by linearisation and consecutive fitting of these equations.

The Planck equation for the radiation intensity of a black body is given by:

$$B_{\lambda} = \frac{2hc^2}{\lambda^5 \left(e^{\frac{hc}{\lambda kT}} - 1\right)}$$

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Or the simplified Wien equation which may be used under the expected circumstances.

$$B_{\lambda} = \frac{2hc^2}{\lambda^5 e^{\frac{hc}{\lambda kT}}}$$

Where;

A black body only exists in the laboratory but a so-called grey body is more common. The overall emission coefficient (ε) of a grey body $(\varepsilon<1)$ is the ratio of the total emitted radiation of the grey body compared to that of a black surface $(\varepsilon=1)$. Certain materials do not obey Planck's law. The emission coefficients can vary with the wavelength. Those materials are called selective radiators. Because the wavelengths used in this investigation are not too far apart, the emissivity of a surface is assumed to be wavelength independent. The emission coefficient also depends on the temperature. During one measurement the temperature has to be constant. If the transmission coefficient is negligible one can derive::

$$r = 1 - \varepsilon$$

Here r is the reflection coefficient.

The emission coefficient is dependent on both the surface structure and the material properties. A rough surface generally results in a relatively low reflection coefficient and thus a high emission coefficient.

With measurements on a grey body the emission coefficient of the surface plays an important role but the temperature of the environment also has an influence. Especially in the case when the temperature of the environment is much higher compared to the temperature of the surface. Then the influence of the environment should also be taken into account. This leads to the following equation:

$$B_{\lambda} = \frac{2hc^{2}}{\lambda^{5}} \left(\frac{\varepsilon}{\frac{hc}{\lambda kT_{o}}} + \frac{1-\varepsilon}{\frac{hc}{\lambda kT_{e}}} \right)$$

Where;

AA TICI	c ,	
В	= the measured radiation energy	$[W/m^2]$
h	= Planck's constant	[Js]
C	= speed of light	[m/s]
k	= Boltzmann's constant	[J/K]
λ	= wavelength of the measurement	[m]
3	= emission coefficients	[-]
T_{o}	= surface temperature	[K]
T_{e}	= environment temperature	[K]

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In this equation ϵ , T_o and T_e are the parameters to be determined.

An example of the Planck curve can be seen in figure 2.

The equations can be solved using a non-linear curve-fitting iteration technique (Marquardt) on a computer.

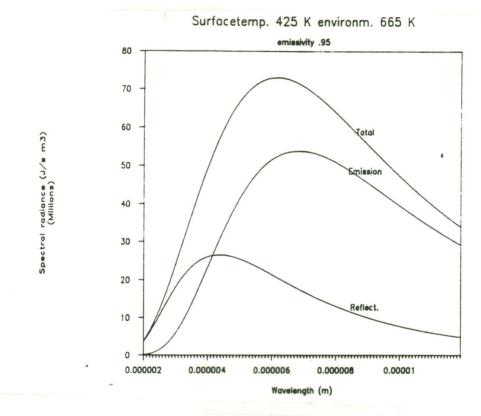


Figure 2 Planck curve, emission and reflection

5.3 The monitor

5.3.1 Introduction

Research was done on how to develop a fouling monitor with the emphasis on measurement of the gas-side surface temperatures of a heat exchanger. Moreover research was done on how to monitor the distribution over the surface of the temperature and the emission coefficient.

A technique which is developed is measurement of radiation at discrete wavelengths. To solve Planck's equation in theory measurements are needed at three wavelengths. To avoid the influence of gases, the discrete wavelengths should not be in the absorption peaks of the gases present (5.3.2).

The design of the monitor hardware, the choice of filters and the detector are described in 5.3.3.

The object temperature and the emission coefficient can be calculated from the infrared radiation emitted from the surface with the aid of an iterative computer program. The software needed for data collection, calculation of the conversion factors and the iterative software are described in 5.3.4.

5.3.2 Absorption of gasses

The preliminary tests were performed with a modified version of the so called gas cloud scanner from TNO [2]. This scanner is an instrument developed at TNO to meet the need to obtain greater insight into the spatial distribution of hazardous gases in work areas. With this scanner one can make IR-images of the distribution of a specific gas in space.

The scanner consists of an infrared emitter, a retro reflector screen, a scanning receiver and a filter system. To examine an indoor space the emitter and receiver are placed on one side of the space and a reflector screen on the other. Many gases and vapours have characteristic absorption peaks in the infrared part of the electromagnetic spectrum. By setting the receiver at the wavelength of this absorption-peak, the user can measure the amount in ppm*m of the specific gaseous component between receiver and reflector screen.

The filter wheel in the scanner can be set on wavelengths between 2.5 and 15.4 micrometer. After slight modifications, this made the scanner suitable for laboratory tests of the principle of the fouling monitor.

The problems encountered in these tests all relate to conversion of the data from the scanner into useable data for the calculation software.

The most important ones are the wavelength dependence of:

- the optical absorption of the atmosphere;
- the transmission of the filter wheel and the lenses;
- the sensitivity of the detector.

In order to find absorption-free windows in the spectrum suitable for the measurements and the correction factors needed for the calculations, scans were made over the spectrum using a near black body and a calibrated infrared source.

The scans gave a number of useable windows roughly between 3.5 and 9 μ m, nicely spread over Planck's curve. In these windows a reliable result from the calculation software can be achieved.

These tests were executed in air. The absorption-free windows which were found are those free of absorption of gases which are common in air, like CO_2 , H_2O etc., see table 1. Gases which can exist in combustion outlets, like SO_2 and NO_x , were also taken in consideration in the selection of absorption-free windows (table 1).

Table 1 Main absorption bands of combustion gases

Nitric Oxide	5.2 μm
Nitrous Oxide	4.4 μm
Carbon Dioxide	2.7 μm
	4.3 μm
Carbon Monoxide	4.8 μm
Sulphor Dioxide	4.1 μm
	7.3 μm
Water	4.8 μm
	6.2 μm

5.3.3 Design of the monitor

It proved very difficult to find a suitable detector which fulfils the spectral requirements obtained from the scanner tests.

Further calculations were therefore performed with the simulation software, using an extra window at approximately 2 μ m. This window is only useful when measuring high temperatures. At higher temperatures the maximum of the Planck curve moves to lower wavelengths. The temperatures in industrial heat exchangers can be relatively high (600 °C), so there can be a sufficiently high level of infrared radiation at 2 μ m.

The final choice for absorption-free windows expected to give satisfactory results were wavelengths between 2.1 - 2.4, 3.4 - 4.1 and $4.6 - 4.8 \mu m$.

For practical reasons the number of filters and the number of measurements at each filter must be kept to a minimum. This is because every measurement, together with the calculations, takes a fair amount of time. In addition the calculations have to be done for each pixel.

The simulation software was also used to find a satisfying number of filters and repetitions. This resulted in the choice of five narrow band filters (2.14, 2.275, 3.48, 3.64 and 4.7 µm) and 10 repetitions (number of measurements at one wavelength).

The advantage of using the region in the infrared spectrum between 2 and 5 μ m is the availability of array detectors, which makes picture generation much easier.

With these restrictions in mind, the market was searched and the result was the purchase of a IRC-64 midwave infrared camera, made by Cincinnatti Electronics. This camera generates a picture of 64 x 64 pixels using an Indium Antimonide detector array without further filtering or signal processing, picture-generation excepted. More detailed information about of the IRC-64 camera is given in Appendix 1.

The developed calculations and signal processing can be performed with a PC and a framegrabber. Other additional hardware incorporated is a set of filters. The filters are controlled by the PC through a motorized filter wheel. A photograph of the camera and the filter wheel is shown in Appendix 2.

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The camera has to be used in the corrected mode. It then corrects internally for the different responses of the pixels. This guarantees a uniform reaction of the different pixels.

Figure 3 shows the optical configuration of the monitor. This differs from the original configuration at two places. The original spectral filter in front of the InSb array is removed and a shiny aluminium pinhole replaces the adjustable iris. The iris is still part of the lens but has to be wide open all the time. The manufacturer advised replacement of an internal correction IC because of the pinhole.

An extra part in the optical configuration is of course the filter wheel. This is a keypad or computer controllable motorized filter wheel from ORIEL for five filters. A DC motor drives the filter wheel and Hall effect sensors detect what number filter is in position. The computer selects the filter number, filter interchange is 1 second for adjacent filters.

The filters used are manufactured by Spectrogon, Sweden. They are narrow band filters with a blocking from the ultraviolet to the far infrared. HW values are from 40 nm for the four shorter wavelength filters to 80 nm for the 4700 nm filter.

The calculations are rather time consuming in the set up with a normal PC, a dedicated chip could solve this problem at a later stage. Now the software only takes a streak 8 x 32 pixels from the picture under consideration.

The camera, framegrabber and filters together with a PC and conversion and iteration software form the monitor.

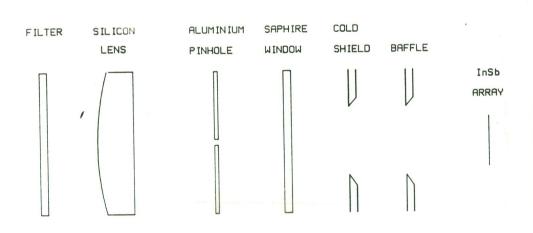


Figure 3 Optical configuration of the camera

5.3.4 Software

The software written for the camera consists of three parts:

- 1. Software which takes care of data acquisition.
- 2. Software which calculates the conversion constant and background radiation of the camera and software which converts binary data files into readable files for the curve fit program.
- 3. Iteration software which calculates the surface temperatures, reflection temperatures and emission coefficients.

1. The data collection software

Data collection with the monitor is performed under pre-set conditions and is separate from the calculations. The calculation software uses data files from the monitor created by this software.

The software takes care of the collection of data from the camera and controls the filterwheel. This software is written in C and compiled with "Microsoft C". The monitor was tested with the program "DATA10.EXE". This program instructs the camera to take 10 frames of 8x32 pixels in the centre of the picture at five different filter settings.

The DATA10.EXE program consists of four parts: the main body, a subroutine to instruct the board to take the specified number of 32K frames, a subroutine to read the collected data in user specified block sizes and a subroutine to set the filter positions.

In the main body the output file, the number of frames and the part of the picture to be examined is specified.

2. Software for calculation of background radiation and conversion factors

The correction factors and background radiation of the camera itself are needed to convert the values from the camera into corrected values for the intensity of the infrared radiation. These correction factors and background radiation are determined with aid of the PASCAL program CORBACK.PAS. The conversion factors correct for the different transparencies of the filters, and other aspects of the camera system. The data files used for calculation of the factors which are the result of calibration tests. The object for data collection in these tests is a black body at a known temperature.

When calculating the correction factors, the user can choose between two options: the first option is to determine the correction factor based on the measurement of one pixel. The second option is to determine the average correction factor from sixteen pixels situated in the middle of the image.

Using the temperature of the black body, the radiation at each of the five wavelengths used is calculated with Planck's formula. These calculations give the theoretical values for the radiation. Using the results of the calculations and the measurements with the camera, a correction factor is determined for each filter.

The camera's background radiation is the radiation of the camera itself on the detector. This is measured by placing a low emitting screen at room temperature just in front of the camera. The background values are determined by calculation of the average of the pixels.

The output of this program is a file with two sets of wavelength dependent numbers:

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background corrections and conversion constants. This output file is needed for the program READRAW.

The purpose of the READRAW program is to convert the 5 binary data files as produced in the laboratory equipment into ASCII readable files for the curve fitting program. This program needs two input files, one input file with wavelength dependent background values and conversion constants, made with the programm CORBACK, and one file with data made by the data collection software.

3. The iteration software

The iteration software PIXELFIT is based on a non-linear curve fitting with Marquardt algorithm and developed by Dr. J.M. Reijn and L.A. Van der Hark of the Department of Computer Support of the Faculty of Pharmacy at Utrecht University, in collaboration with TNO.

The Marquardt algorithm [3] is a convenient algorithm which combines the best features of the gradient search with the method of linearizing. The fitting function can be obtained by increasing the diagonal terms of the curvature matrix by a factor which controls the interpolation of the algorithm between the two extremes.

This program needs the input file made by READRAW.

The software is tested with simulation software which created data with varying noise, wavelengths and temperatures.

During and after these tests the software was optimized and the required conditions for the measurements were set.

5.4 Practical monitor tests

5.4.1 Introduction

The second part of the project is to check the correctness of the calculated emission coefficient and surface temperatures. A test facility is therefore built up in which several surfaces are measured.

Afterwards the design of the camera is looked at. The most important question is whether the camera is suitable for use under industrial conditions.

5.4.2 Experimental set up

The testing of the fouling monitor is divided into 3 phases:

- 1. Experiments on a heated tube at room temperature;
- 2. Experiments on a cooled tube in a hot surrounding (in an oven);
- 3. Experiments on an industrial heat exchanger.

The first and second phases take place in the laboratory, the third phase of the experiments might take place at an industrial heat exchanger. The preparations have been made for the first two experiments and are described in this report.

The aim of the first two experiments is to test the principle of the method and to determine whether the temperatures and the emission coefficients measured and calculated by the monitor are in accordance with each other. The surface temperatures and emission coefficients are therefore being measured by alternative methods and the results of the two measurements will be compared.

The monitor is restricted because it can not measure accurately below a certain amount of radiation. When the temperature of the surface decreases the radiation from the surface will also decrease. So this will lead to a minimum temperature the monitor can measure.

5.4.3 Practical preparations

5.4.3.1 Test tubes

The measurements are done on test tubes with different surfaces. For the first and second experimental phases fouled tube surfaces are created with different emission coefficients. The test tubes are fouled with the following materials:

- 1. Copa-slip: a mixture of lead, copper and bentone, a heat resistant paste used for protection of screws at high temperatures;
- 2. Black paint mixed with a sodium silicate solution;
- 3. Heat resistance mortal mixed with a sodium silicate solution;
- 4. Sable sand mixed with a sodium silicate solution fixed on fibrafax.

In the tubes a groove is made in which the thermocouples are adjusted. The surface thermocouples measure the temperature of the tube just under the surface of the fouling layer. The thermocouple is fixed just a little below the surface to be sure that we measure the surface temperature and not the temperature of the surrounding gas. The surface temperature as calculated by the monitor will be compared to the temperature measured by the thermocouples.

5.4.3.2 Experiments on a heated tube at room temperature

Purpose: Measuring the relationship between the surface temperature and the emission coefficient of the surface.

The tube is attached between two clamps at a height of 1 m. The tubes are heated from the inside with a heating element. During the experiments the temperature is varied from 300 to 600 degrees Celsius. During the experiments the surface temperature is measured with a thermocouple.

When the temperature of the tube is varied the emission coefficient changes because it depends on the temperature. The emission coefficients are measured by two infrared cameras Cyclops 33, and AGA 780 working in different wavelength intervals (8-14 μ m and 3-5.6 μ m respectively). The cameras are placed perpendicular to the tube.

After these experiments the emission coefficients are known at various surface temperatures for the various tubes. This relationship will be used in the second experimental phase in a hot environment.

5.4.3.3 Experiments in a hot surrounding

Purpose: Experimental determination of whether the monitor measures and calculates the correct emission coefficients and the right surface

temperatures when it is in a hot environment.

The experiments take place in an electric tubular oven (Figure 4) into which the fouled tubes are inserted. The temperature of an inner alumina tube (inner diameter 10 cm, length 60 cm) can be varied over a temperature range from 25 to 1000 degrees Celsius.

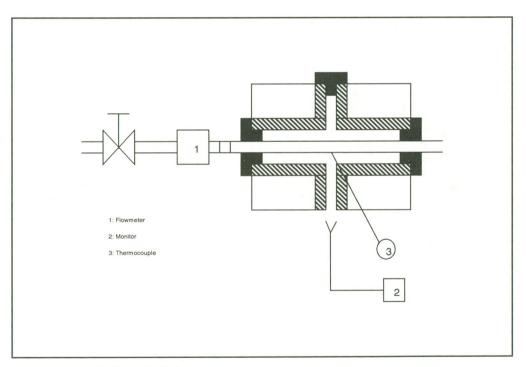


Figure 4 Test facility cooled tube in oven

The oven can be adjusted by three independent voltage sources. Each source regulates one part of the oven. Axial energy losses are reduced by thermal insulation of both ends. A hole (diameter 3.5 cm) in the side of the tubular oven permits monitoring of the test tube surfaces.

The tubes are placed in the oven and are cooled with an airstream from inside.

The surface temperature is measured by a thermocouple and is compared with the temperatures measured by the monitor.

In the first set of experiments the relationship was made between the emission coefficient of the surface and the surface temperature. These results can be used again to judge whether the emission coefficient determined by the monitor is correct.

The monitor is calibrated just before each measurement. A conical plug is placed in the oven. With the camera facing the plug, the plug appears as a black body. The correction factors are calculated with the CORBACK program.

5.4.4 Measuring Equipment

Thermocouples

The temperatures are measured with chromium alumal thermocouples.

Infrared cameras

The emission coefficient and the temperature of a surface can be measured by infrared detectors. At a known surface temperature and known ambient temperature the emission coefficient is derived from the equation:

$$\epsilon \, = \, \frac{Q - \sigma T_e^4}{\sigma \, (T_0^4 - T_e^4)}$$

Where:

Q: intensity of the radiation

σ : Stefan's constant

 $[W/m^2]$ $[W/m^2K^4]$

The temperature of the surface must be known when the emissivity of a surface is being measured. For these experiments two infrared cameras are available. More specifications of these cameras can be found in Appendix 1.

6 Results and discussion

6.1 Results

Final experiments have been done on only one tube: black paint mixed with a sodium silicate solution. Only one tube has been measured because the results of the first measurements showed large deviations. The method should first be improved before measurements on the other tubes are undertaken. Experiments are done at 5 different tubular oven temperatures. A set of measurements is made at each condition. The monitor measures the radiation of the surface and the object temperature, emission coefficient and reflection temperature of the environment are calculated with the curve fit program.

The results of the monitor experiments are listed in Appendix 3. Several recordings are made for one set of measurements at one temperature. Calculations have been made for three pixels for the different recordings. The results of these experiments are screened. Experiments with extreme results compared with the other experiments in the same set or which ended in a run-time error are ignored and rejected. The rejected experiments are marked with an asterisk(*) in Appendix 3.

The average of the object temperature, reflection temperature and emission coefficient will be determined for each set of measurements.

The formula used for this is:

$$X_{average} = \frac{1}{n} \sum X_i$$

X = parameter

n = number of measurements

The estimator of the variance of the experiments is also calculated. The root of the variance (σ_{n-1}) is an estimator of the average spread of the calculated temperatures or emission coefficients. For a good experiment this spread should be small. The formula used for the calculation of σ_{n-1} is:

$$\sigma_{n-1} = \sqrt{\frac{1}{n-1} \sum (X_i - X_{average})^2}$$

The analysis of the results is broken down into three parts. In the first part the object temperature calculated by the monitor will be compared with the object temperature measured with the thermocouple (6.1.1). Because we intend to measure surface temperatures this parameter is the most important. Secondly the calculated emission coefficient will be compared with the measured emission coefficient (6.1.2) relating to the object temperature. And finally the reflection temperatures will be examined (6.1.3)

6.1.1 Comparison of the surface temperature

The surface temperature measured with the monitor (using the curve fit program) is compared with the temperature measured by a thermocouple attached to the surface.

The temperature of the surface measured by a thermocouple is listed in the first column of Table 2. The second column represents the number of measurements in that set of experiments, the third column represents the average of the calculated surface temperature and the fourth column represents the deviation of the object temperature, which is a degree of the spread in temperatures. The last columns represent the absolute and relative difference between the surface temperature measured by the thermocouple and the temperature measured by the monitor.

Thermocouple measurement	Meas	urement with	_ T _{o,n}	parison nonitor mocouple	
T _{o,thermo} [Kelvin]	n [-]	Average T _{o,monitor} [Kelvin]	σ _{n-1} [Kelvin]	Absolute difference [Kelvin]	Relative difference [%]
639	17	653	7	14	2.1
683	12	690	17	7	1
712	15	687	21	25	3.5
738	4	727	12	11	1.4
807	8	720	44	87	10

Table 2 Surface temperatures (T_o)

It can be seen that the relative difference (column 6) between the thermocouple and monitor temperatures is less than 5 percent for the first, second, third and fourth set of experiments, which is quite good. From this standpoint it can be said that the monitor calculates the surface temperatures satisfactorily.

The average absolute fault in the measured temperature is 14 °C, in the first set of experiments and in the third set of experiments 25 °C. Though the relative fault (column 6) between the temperature measured by the monitor and the temperature measured by the thermocouple is less than 5 percent, the absolute fault (column 5) in these sets of experiments is quite large.

The deviation (column 4) of the calculated surface temperature is quite large, especially for the second, third and fifth sets of experiments. This means the calculated surface temperature of the monitor has a wide spread. For a good experiment this spread should be smaller.

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In summary: The calculation of the surface temperature is not satisfactory.

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6.1.2 Comparison of the emission coefficient

The emission coefficient measured by the monitor is compared with the emission coefficient of a heated tube measured by the two infrared cameras. The emission coefficient of a surface depends on the temperature of the surface. To determine the emission coefficient of a surface experiments are done at room temperature and the relationship between the surface temperature and the emission coefficient is measured separately with two infrared cameras. The results are listed in Table 3.

Table 3 Relation between emission coefficient and surface temperature

Surface temperature [Kelvin]	Emission coefficient Cyclops	Emission coefficient AGA
638	0.86	0.80
653	0.84	
731	0.87	0.80
744	0.84	
781	0.84	
807	0.87	0.80

From these results it is obvious that in this case measured emission coefficients hardly depend on the surface temperature. It can therefore be assumed that the emission coefficient is constant. The emission coefficient measured by the AGA and Cyclops were 0.80 and 0.86 respectively. These values are averaged in column three of Table 3. The inaccuracy of the measurement is 0.04, so the emission coefficient of the surface is 0.83 plus or minus 0.07. This emission coefficient (column four, Table 4) is used for comparison with the emission coefficient measured with the monitor. The average of the emission coefficients and its deviation are determined from monitor measurements and are given in Table 4.

Table 4 Emission coefficients (E)

M	lonitor measureme	Measurement by two infrared cameras	
n [-]	Average emission coefficient	σ _{n-1}	Average emission coefficient
17	0.958	0.017	0.83
12	0.735	0.053	0.83
15	0.75	0.14	0.83
4	0.75	0.038	0.83
8	0.54	0.2	0.83

It can be seen that the average emission coefficients of the second, third and fourth sets of experiments measured by the monitor are close to the emission coefficient determined by the infrared cameras. The fifth set of experiments shows an emission coefficient which is too low and the first set of experiments shows an emission coefficient which is too high.

The deviation (σ_{n-1}) of the third (0.14 or 19%) and fifth (0.2 or 37%) sets of experiments is very large, yet for a good experiment this spread should be small. In summary, only the calculations of the emission coefficients in sets 2 and 4 are satisfactory. Sets 1, 2 and 5 of experiments have either a deviation or an absolute fault which is too large.

6.1.3 The reflection temperature

The reflection temperature itself, the average and the deviation are listed in Table 5 to give an impression of the reflection temperatures calculated by the monitor. Because it is very difficult to measure reflection temperatures separately, they can not be compared with other data.

Only the deviation of the reflection temperatures calculated by the monitor is examined.

Table 5 Reflection temperatures (T_c)

irement mo	nitor
n [-]	G _{n-1} [Kelvin]
17	320
12	19
15	67
4	7.8
8	50
	n [-] 17 12

From Table 5 it can be seen that in particular the deviation of the first, third and fifth sets of experiments is large (more than 5%), which again is too large.

6.2 Discussion

Results

The differences between the object temperature and the emission coefficient measured by the monitor are in some cases relatively large compared with the separately measured temperature and emission coefficient. The deviation of the calculated parameters is also too large in most cases. This is probably caused by the following aspects:

- 1. The first aspect which is very important for the result of the surface temperature and emission coefficient calculated by the monitor is the quality of the dataset offered to the iteration program. During the experiments it became obvious that the response of the camera was not constant in time. This is probably caused by a loss of vacuum.
- 2. There is a large fluctuation in the raw data measured by the camera. This fluctuation in input data is sometimes more than 15 percent. These data are the input data for the iteration program. This fluctuation in input data will be relatively large for the lowest wavelength because then the absolute value of the radiation is small. This situation occurs during measurement at the smallest wavelengths $(2.14 \, \mu m$ and (2.275) at low temperatures $(T=650-700 \, K)$.

A solution to this problem could be to base the datafit only on the three highest wavelengths during measurement at low temperatures. In addition the number of measurements at one wavelength can be raised, so the calculations will be more exact.

A second solution to this problem could be to screen the raw data measured by the camera and to reject extreme data points.

A third solution could be the use of another detector or another camera which is more sensitive and fluctuates less.

Finally the probable loss of vacuum should be examined.

3. The results determined by the iterative software have a mathematical fault which in some cases is more than 30% for the calculated emission coefficient, more than 10% for the object temperature and more than 10% for the reflection temperature. This poor convergence of the software can be caused by bad choices of initial estimators, by the fact that the iteration method is not suitable for solving that set of equations or it can be caused by the fluctuations in the input data of the iteration program.

The results of the measurements are still moderate, however, and it is expected that by improvement of the stability of the measuring method, the quality of the input data for the iteration program can be improved. This will probably result in more exact calculation of the surface temperatures and emission coefficients.

Design of the Camera

During the measurements the design of the camera is examined. During the experiments the following was revealed:

Because the monitor is a pilot model, there are still some weak points in the design of the monitor. The monitor is not yet suitable for use in environments with dust and aggressive components or water. Integrating the filters in the camera, for example, would make the system more robust. Another possibility is to place the camera in a box which is kept at a higher pressure than the environment. This protects the monitor against dust and harmful components.

The camera is cooled with liquid nitrogen. Another cooling system makes the camera easier to handle.

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7 Economic assessment

8 Future work

Experiments showed that the response of the camera was not constant in time. There is a fluctuation in measuring data which, especially for the lower wavelength, is sometimes more than 15 percent. This fluctuation in input data is relatively large while the absolute values of the input data are small. The stability of the measuring method should therefore be improved.

The software consists of separate programs. The data collection and iteration software should be integrated.

In one run of the iteration software one pixel is calculated. The software should be adapted to calculate an array of pixels.

Integrating the filters in the camera would make the system more robust. A cooling system other than liquid nitrogen makes it easier to handle.

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9 References

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 P.R. Bevington,
 Data Reduction and Error Analysis for the Physical Sciences

10 Authentication

Name and address of the principal
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Names of establishments to which part of the research was put out to contract Department of Compute Support Faculty of Pharrmacy Utrecht University

Date upon which, or period in which, the research took place $July\ 1990$ - $Jaunary\ 1993$

Signature

Ir. S.I. Timmerman research coordinator

in norman

Ir. H.C. van Deventer section leader

Appendix 1 Technical Specifications

Specification of the camera (IRC-64):

spectral respons:

1-5.5 µm

detector:

Indium Antimode(IsSb)

number of elemnets:

4096 (64*64) discrete detector elements

pixel pitch:

100 μm

pixel size: focus distance: 55 μm

colling distance.

3 feet to infinity

field of view:

7.3 degrees * 7.3 degrees

resolution:

2 * 2 milliradian

Minolta/Land, type Cyclops 33, infrared spotmeter:

spectral respons:

8 - 14 µm

— temperature range:

0 - 100°C

emission coefficient

0.3 - 1.00 (minimal stepwidth 0.01)

minimal spot size:

13 mm at 0.75 m

AGA Thermovision type 780, infrared camera:

– spectral response:

3 - 5.6 μm

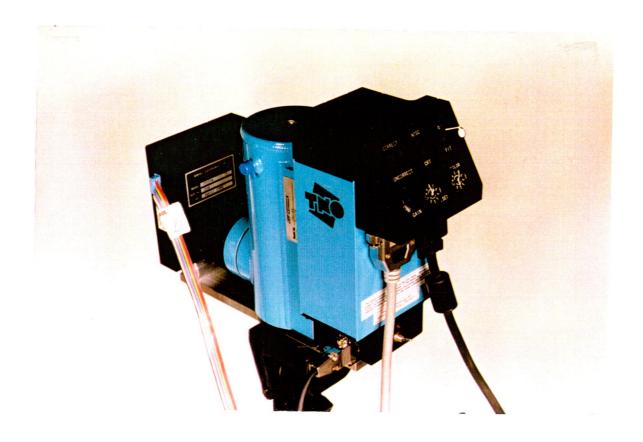
— temperature range:

-20 - 850 °C

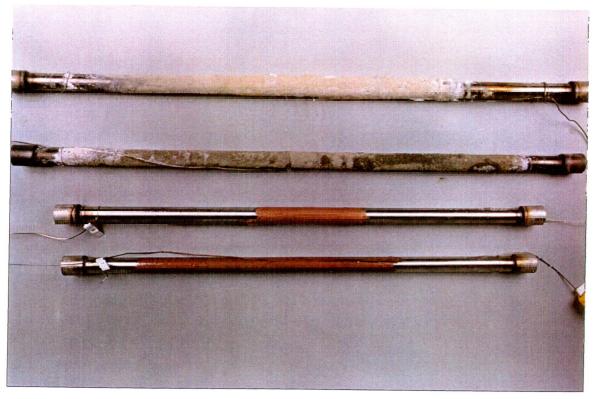
– emission coefficient:

0.3 - 1.00 (minimal stepwidth 0.01)

Appendix 2 Photographs



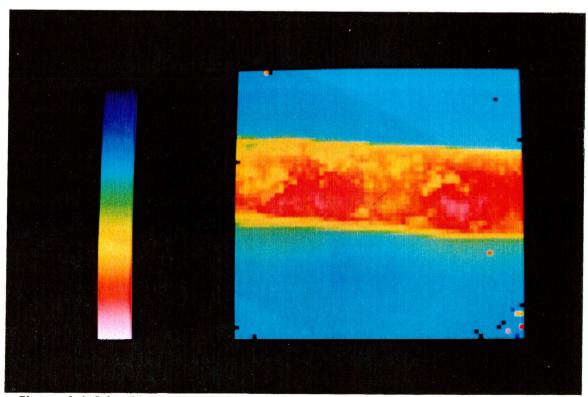
Photograph 1 Monitor and filterwheel



Photograph 2 Fouled test tubes



Photograph 3 Tubular oven



Photograph 4 Infrared image of heated tube, recorded by the IRC camera

Appendix 3 Results of monitor calculations

The results of the calculations of the iterative programme are listed. The results are divided in 5 set of experiments. One set of experiments consists of the measurments at one temperature of the oven.

The name of the experiment is written down after 'data:'

The number of iterations tells how many iteration loops are done (maximum of 20). The sum of squares "SSQ" is the value which is minimalised by the iterative programme and is given by the following formula:

$$SSQ = \sum_{i=1}^{n} (y_{data}(i) - y_{fit}(i))^{2}$$

The iterattive programme calculates the values and the mathematical faults for the emission coefficient(=epsilon), the surface temperature (object) and the reflection temperature (environment). The temperatures are in Kelvin.

The absulute value, the relative mathematical fault [%] and the absolute mathematical fault in the three parameters are listed for every experiment.

Set experiments 1

Results fit						
data: 123.PI	X, a367a23	3				
Sum of square						
Number of ite						
			4.0052	ahaalusta		0.0472
epsilon		fault in %:	4.9052			0.0472
,		fault in %:	1.2220			8.0558
environment	897.4546	fault in %:	13.8357	absolute	:	124.1688
Results fit						
data: 132.PI	V 9367933)				
Sum of square						
Number of ite		20	0 = 1 1 0			0.0010
epsilon				absolute		0.0242
object	647.5568	fault in %:	0.9791	absolute	:	6.3400
environment	955.0687	fault in %:	6.3096	absolute	:	60.2608
Results fit						
	N -267-41					
data: 141.PI	-					
Sum of square)				
Number of ite	erations:	20				
epsilon	0.9674	fault in %:	1.3365	absolute	:	0.0129
object	649.8945	fault in %:	0.6504	absolute	:	4.2271
environmnet				absolute		53.8194
	1000.1990	14411 /0.	3.3300	accorate		33.0131
Results fit						
data: 123.PI	X, a367b23	3				
Sum of square	es 3.2208	3				
Number of ite	erations:	20				
epsilon	0.9554	fault in %:	2.2542	absolute	:	0.0215
		fault in %:	0.8934	absolute	:	5.8023
environment			5.9665			
CIIVIIOIIIICIIL	700.0340	lault III /0 .	3.7003	absorate		37.3100
Results fit						
data: 132.PI	X, a367b32	2				
Sum of square	es 4.2435	5				
Number of ite	erations:	20				
epsilon	0.9751	fault in %:	0.9435	absolute	:	0.0092
object	651.1083		0.6014			3.9159
environment			5.4326			58.4666
environment	1070.2097	fault III 70.	3.4320	absolute	•	36.4000
Results fit						
data: 141.PI	X, a367b41	l				
Sum of square						
Number of ite		20				
epsilon		fault in %:	1.9933	absolute		0.0191
_						
object		fault in %:	0.8376			5.4476
environment	981.7848	fault in %:	6.1987	absolute	:	60.8582

data: 122 DIV 226				
data: 123.PIX, a36				
Sum of squares 2.				
Number of iterations				
1	428 fault in %:		absolute	
object 645.8			absolute	
environment 940.9	988 fault in %:	6.0636	absolute	57.0583
Results fit				
data: 132.PIX, a36	7c32			
Sum of squares 2.				
Number of iterations	: 20			
epsilon 0.9	397 fault in %:	2.6768	absolute :	0.0252
object 642.2	467 fault in %:	1.0850	absolute :	6.9684
environment 952.7	954 fault in %:	5.1792	absolute :	49.3470
Results fit				
data: 141.PIX, a36	7c41			
Sum of squares 3.				
Number of iterations				
epsilon 0.9	709 fault in %:		absolute :	0.0122
object 650.7	289 fault in %:	0.7110	absolute :	4.6267
environment 1044.5			absolute :	
7.2				
**Results fit				
data: 123.PIX, b36				
Sum of squares 10.				
-				
Number of iterations				
Number of iterations epsilon 0.8	827 fault in %:**			9528.0128
Number of iterations epsilon 0.8 object 670.7	827 fault in %: ** 471 fault in %: 33	370.9558	absolute :	*****
Number of iterations epsilon 0.8	827 fault in %: ** 471 fault in %: 33	370.9558	absolute :	
Number of iterations epsilon 0.8 object 670.7	827 fault in %: ** 471 fault in %: 33	370.9558	absolute :	*****
Number of iterations epsilon 0.8 object 670.7 environment 674.9	827 fault in %: ** 471 fault in %: 3: 101 fault in %: **	370.9558	absolute :	*****
Number of iterations epsilon 0.8 object 670.7 environment 674.9	827 fault in %: ** 471 fault in %: 3: 101 fault in %: **	370.9558	absolute :	*****
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36	827 fault in %: ** 471 fault in %: 3: 101 fault in %: ** 7a32	370.9558	absolute :	*****
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4.	827 fault in %: ** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20	370.9558 *******	absolute :	*****
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9	827 fault in %: ** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20	370.9558 ******* 3.7586	absolute : absolute :	******* ******************************
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7	827 fault in %: ** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %:	370.9558 ******* 3.7586 1.1841	absolute : absolute : absolute : absolute :	0.0360 7.7293
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7 environment 920.0	827 fault in %: *** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %: 383 fault in %:	370.9558 ******* 3.7586 1.1841	absolute : absolute : absolute : absolute :	0.0360 7.7293
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7 environment 920.0 Results fit	827 fault in %: ** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %: 383 fault in %: 651 fault in %:	370.9558 ******* 3.7586 1.1841	absolute : absolute : absolute : absolute :	0.0360 7.7293
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7 environment 920.0 Results fit data: 141.PIX, b36	827 fault in %: ** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %: 383 fault in %: 651 fault in %:	370.9558 ******* 3.7586 1.1841	absolute : absolute : absolute : absolute :	0.0360 7.7293
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7 environment 920.0 Results fit	827 fault in %: *** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %: 383 fault in %: 651 fault in %:	370.9558 ******* 3.7586 1.1841	absolute : absolute : absolute : absolute :	0.0360 7.7293
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7 environment 920.0 Results fit data: 141.PIX, b36 Sum of squares 8. Number of iterations	827 fault in %: *** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %: 383 fault in %: 651 fault in %:	3.7586 1.1841 9.5131	absolute : absolute : absolute : absolute :	0.0360 7.7293 87.5271
Number of iterations epsilon 0.8 object 670.7 environment 674.9 Results fit data: 132.PIX, b36 Sum of squares 4. Number of iterations epsilon 0.9 object 652.7 environment 920.0 Results fit data: 141.PIX, b36 Sum of squares 8. Number of iterations epsilon 0.9 object 0.9 obj	827 fault in %: *** 471 fault in %: 3: 101 fault in %: ** 7a32 9211 : 20 570 fault in %: 383 fault in %: 651 fault in %: 7a41 8882 : 20	3.7586 1.1841 9.5131 0.1003	absolute : absolute : absolute : absolute : absolute :	0.0360 7.7293 87.5271

	es 4.0219 erations: 0.9496 651.9534	20 fault in ' fault in '	%:	4.2306 1.2477 8.5825		:	0.0402 8.1346 77.5038
Results fit data: 132.PI Sum of square Number of ite epsilon object environment	es 4.0153 erations: 0.9990 666.3504	3 20 fault in ' fault in '	%:	0.2080	absolute	:	0.0007 1.3859 396.0742
1	es 4.8082 erations: 0.9355 649.3123	20 fault in fault in f	%:	5.5307 1.4653 8.3801	absolute	:	9.5146
Results fit data: 123.PI Sum of square Number of ite epsilon object environment	es 2.7202 erations: 0.9455 650.8154	20 fault in fault in f	%:	1.3594	absolute absolute	:	0.0435 8.8472 79.3318
Results fit data: 132.PI Sum of square Number of ite epsilon object environment	es 2.3931 erations: 0.9632 652.3623	1 20 fault in ' fault in '	%:	2.3751 0.9678 7.7262	absolute absolute absolute	:	0.0229 6.3133 74.9515
Results fit data: 141.PI Sum of square Number of ite epsilon object environment	es 2.9525 erations: 0.9987 666.2716	20 fault in fault in	%:	0.1020 0.2414 19.7786		:	0.0010 1.6086 345.4097

Set experiments 2

built of square	IX, a410a23 es 1.4223				
Number of ite		3			
epsilon		fault in %:			0.8360
object					61.4466
environment	796.5619	fault in %:	15.7646	absolute:	125.5750
Results fit data: 132.PI					
Sum of square					
Number of ite			16 6157	-la-al	0.2402
epsilon object		fault in %:		absolute:	
environment				absolute:	
environment	013.0340	fault III 70.	0.4119	absolute.	00.9333
Results fit	DZ - 410 - 41				
data: 141.PI Sum of square					
Number of ite					
epsilon		_	41.2546	absolute :	0.2785
object				absolute :	37.7424
environment				absolute:	51.8733
Results fit data: 123.PI Sum of square Number of ite	es 1.6664				
epsilon		fault in %:	85.9036	absolute:	0.6926
object		fault in %:	7 1220	1 1	
			1.1230	absolute:	50.5581
environment	810.8040	fault in %:		absolute :	
Results fit data: 132.PI	X, a410b32	2			
Results fit data: 132.PI Sum of square	X, a410b32	2			
Results fit data: 132.PI Sum of square Number of ite	X, a410b32 es 1.1967 erations:	2 7 4	19.7003	absolute :	159.7310
Results fit data: 132.PI Sum of square Number of ite epsilon	X, a410b32 es 1.1967 erations: 0.8206	2 7 4 fault in % :	19.7003 27.3202	absolute :	159.7310 0.2242
Results fit data: 132.PI Sum of square Number of ite	X, a410b32 es 1.1967 erations: 0.8206 690.2353	2 7 4 fault in % : fault in % :	19.7003 27.3202 4.0476	absolute :	159.7310 0.2242
Results fit data: 132.PI Sum of square Number of ite epsilon object environment Results fit data: 141.PI Sum of square	X, a410b32 es 1.1967 erations: 0.8206 690.2353 848.9736 X, a410b41 es 1.0786	fault in %: fault in %: fault in %:	19.7003 27.3202 4.0476	absolute : absolute : absolute :	0.2242 27.9382
Results fit data: 132.PI Sum of square Number of ite epsilon object environment Results fit data: 141.PI	X, a410b32 es 1.1967 erations: 0.8206 690.2353 848.9736 X, a410b41 es 1.0786 erations:	fault in %: fault in %: fault in %:	19.7003 27.3202 4.0476 9.6392	absolute : absolute : absolute :	0.2242 27.9382
Results fit data: 132.PI Sum of square Number of ite epsilon object environment Results fit data: 141.PI Sum of square Number of ite	X, a410b32 es 1.1967 erations: 0.8206 690.2353 848.9736 X, a410b41 es 1.0786 erations: 0.7292	fault in %: fault in %: fault in %: fault in %:	19.7003 27.3202 4.0476 9.6392	absolute : absolute : absolute : absolute :	0.2242 27.9382 81.8342

Results fit data: 123.PI Sum of square Number of ite epsilon object environment	es 1.0880 erations: 0.7167 713.5562) 4 fault in % fault in %	: 19.6712		:	140.3653
Results fit data: 132.PI Sum of square Number of ite epsilon	es 1.6536	5 4	. 72 1708	absolute		0.5242
1	690.6177					
environment						91.8291
Results fit data: 141.PI Sum of square Number of ite epsilon object	es 1.5516 erations: 0.6540 671.0976	6 4 fault in % fault in %	: 7.2096		:	0.4023 48.3833
environment	798.1487	fault in %	: 7.8821	absolute	:	62.9111
Results fit data: 123.PI. Sum of square Number of ite epsilon object environment	es 1.3286 erations: 0.7782 713.4258	4 fault in % fault in %			:	1.7142 91.7922 261.0876
Results fit data: 132.PI Sum of square Number of ite epsilon object environment	es 1.1661 erations: 0.8137 693.3238		: 5.0707	absolute	:	0.3264 35.1567 102.6437
Results fit data: 141.PI. Sum of square Number of ite epsilon	es 1.1616 erations:		. 41 2013	absolute		0.2962
object		fault in %				36.7551
environment	814.9821					61.9829
	and the second second second second					

Set experiment 3

Results fit data: 123.Pl Sum of square Number of ite epsilon object environment	es 3.5949 erations: 0.6975 678.0018	4 fault in %: fault in %:	32.8017 4.7249 5.8051		:	0.2288 32.0348 48.2226
**Results fit data: 132.PI Sum of square Number of ite epsilon object environment	es 6.4900 erations: 0.2948 539.6372	20 fault in %: fault in %:			:	0.0480 35.9281 6.0335
Results fit data: 141.PI Sum of square Number of ite epsilon	X, a439a41 es 6.1208 erations: 0.7308 677.2101	1 3 4 fault in %: fault in %:		absolute absolute	:	0.1756 25.5421 44.4166
Results fit data: 123.PI Sum of square Number of ite epsilon object environment	es 1.4451 rations: 0.7682 690.2126	4 fault in %: fault in %:	4.3821		:	0.2391 30.2460 65.5637
Results fit data: 132.PI Sum of square Number of ite epsilon object environment	es 1.5460 rations:		21.8736 3.8013 5.6950		:	0.1652 25.7930 48.7316
Results fit data: 141.PI Sum of square Number of ite epsilon object environment	es 3.5540 rations: 0.7753 686.4352	fault in %:	21.5772 3.2416 5.8422	absolute	:	0.1673 22.2515 49.4199

Results fit data: 123.PIX, a439c23 Sum of squares 2.7463 Number of iterations: 11							
epsilon			8.8134	absolute:	0.0838		
object					12.8580		
		fault in %:		absolute :			
Results fit							
data: 132.P	IX, a439c32	2					
Sum of square	es 1.4404	4					
Number of ite		20					
_		fault in %:	7.0718	absolute:	0.0639		
object		fault in %:	1.5370	absolute:	10.7736		
environment	922.2137	fault in %:	6.4041	absolute:	59.0594		
Results fit	137 420 4	•					
data: 141.P							
Sum of square Number of ite		20					
		fault in %:	1 8101	absolute :	0.0177		
object		fault in %:	0.7052		5.0083		
environment				absolute:	89.7149		
CIIVIIOIIIICIIC	1031.3101	14411 111 70.	0.3013	descrate.	03.1113		
**results fit							
data: 123.Pl	X, b439a23	3					
Sum of square							
Number of ite	erations:	20					
epsilon	0.2686	fault in %:	65.2092	absolute:	0.1752		
object	600.6774	fault in %:	12.9377	absolute:	77.7137		
environment	767.9902	fault in %:	2.0548	absolute:	15.7806		
**results fit							
data: 132.Pl							
Sum of square							
Number of ite			141600	1 1	0.0000		
		fault in %:		absolute:			
object	162 0500	C 1. ' 0/	10 1100	1 1	E7 7112		
		fault in %:		absolute:	57.7413		
environment		fault in %: fault in %:		absolute :	57.7413 3.5561		
Results fit	767.5635	fault in %:					
Results fit data: 141.Pl	767.5635 IX, b439a4	fault in %:					
Results fit data: 141.Pl	767.5635 IX, b439a4 es 7.2872	fault in %:					
Results fit data: 141.Pl Sum of square Number of ite	767.5635 IX, b439a4 es 7.2872 erations:	fault in %: 1 2 20	0.4633		3.5561		
Results fit data: 141.Pl Sum of square Number of ite	767.5635 IX, b439a4 es 7.2872 erations: 0.3835	fault in %: 1 2 20 fault in %:	0.4633 56.7296	absolute :	3.5561 0.2176		
Results fit data: 141.Pl Sum of square Number of ite	767.5635 IX, b439a4 es 7.2872 erations: 0.3835	fault in %: 1 2 20 fault in %: fault in %:	0.4633 56.7296 9.2634	absolute :	3.5561		

Results fit data: 123.PI Sum of square Number of ite epsilon object environment	es 1.670 erations: 0.6836 691.4822	3 fault in %: fault in %:	82.4721 8.1807 10.8274		:	0.5638 56.5684 87.1834	
Results fit data: 132.PI Sum of square Number of its epsilon object	erations: 0.6800 677.6001	4 fault in %: fault in %:	5.9635		:	0.3004 40.4083	
Results fit data: 141.PI		fault in %:	6.8522	absolute	:	56.2914	
Sum of square	es 3.749	1					
Number of ite epsilon		fault in %:	54 0872	absolute		0.3641	
object		fault in %:	5.9097			40.4531	
environment				absolute		58.0921	
Results fit data: 123.PIX, b439c23 Sum of squares 1.5603 Number of iterations: 4							
epsilon		fault in %:	103.6199	absolute	:	0.8334	
object		fault in %:	8.4193	absolute	:	60.0387	
environment	813.0636	fault in %:	23.1843	absolute	:	188.5033	
Results fit data: 132.PI Sum of square Number of its epsilon object			31.9829 4.1345	absolute absolute	: :	0.2341 28.3063	
environment	825.3415	fault in %:	6.2464		:	51.5538	
Results fit data: 141.PI Sum of square Number of ite							
epsilon	0.7938	fault in %:	24.0035	absolute	:	0.1905	
object		fault in %:	3.2812	absolute	:	22.5697	
environment	007 0010	fault in %:	7.0369	absolute		58.9196	

Set experiments 4

object	es 8.9128 erations: 0.9517 772.0187		918.2166	absolute	: 1838.2544 : 7088.8044 : *******
object	es 2.1145 erations: 0.7915 738.2016	5 5 fault in % :	5.7870	absolute	: 0.5108 : 42.7194 : 123.9324
Results fit data: 141.Pl Sum of square Number of ite epsilon object environment	es 2.2567 erations: 0.7636 720.2849	7 5 fault in % : fault in % :	30.3981 3.9175 7.2242	absolute	
Results fit data: 123.PI Sum of square Number of ite epsilon object environment	es 8.9380 erations: 0.9465 773.1302) 11 fault in % : **	586.8929	absolute	: 943.0529 : 4537.4467 : *****
Results fit data: 132.PI Sum of square Number of ite epsilon object environment	es 2.1855 erations:		72.3116 6.2605 14.2904		
Results fit data: 141.PI Sum of square Number of ite epsilon object environment			39.2014 4.8389 6.7888		

Set experiments 5

_	7 20 fault in %: fault in %:	9.2528	absolute absolute absolute	: 50.3195
**Results fit data:132.pix, a534a32: 1	runtime error			
**Results fit data:141.pix, a534a41: r	runtime error			
Results fit data: 123.PIX, a534b2 Sum of squares 2.562 Number of iterations: epsilon 0.3358 object 691.6608 environment 869.7894	3 20 fault in %: fault in %:	10.5799	absolute absolute	: 73.1767
Results fit data: 132.PIX, a534b3 Sum of squares 2.312 Number of iterations: epsilon 0.3135 object 660.4013 environment 871.0205	20 fault in %: fault in %:	6.2413	absolute absolute	: 41.2178
*	7 20 fault in %: fault in %:	6.3521	absolute absolute	: 42.3168
Results fit data: 123.PIX, b534a2 Sum of squares***** Number of iterations: epsilon 0.7790 object 635.1952 environment 1204.6799	* 20 fault in %: fault in %:	0.5661 0.5227 0.3486		3.3202

Results fit							
data: 132.PIX, b534a32							
Sum of squares 16.7466							
Number of iterations: 6							
epsilon	0.6497	fault in %:	22.0910	absolute	: 0.1435		
object	750.3536	fault in %:	3.0381	absolute	: 22.7967		
environment	918.0098	fault in %:	3.2219	absolute	: 29.5774		
Results fit							
data: 141.Pl	X, b534a4	1					
Sum of square							
Number of ite	erations:	20					
epsilon	0.9086	fault in %:	6.0261	absolute	: 0.0548		
object	782.5816	fault in %:	1.2441	absolute	9.7358		
environment	1032.1955	fault in %:	6.0802	absolute	: 62.7596		
Results fit							
data: 123.PI	X, b534b23	3					
Sum of square							
Number of ite	erations:	5					
epsilon	0.6278	fault in %:	42.4951	absolute	: 0.2668		
object	750.2398	fault in %:	5.8045	absolute	: 43.5475		
environment	916.6000	fault in %:	5.5541	absolute	: 50.9088		
Results fit							
data: 132.PI	X. b534b32	2					
Sum of square	es 4.3142	2					
Number of ite	erations:	6					
epsilon	0.5737	fault in %:	20.5935	absolute	: 0.1181		
object		fault in %:	3.3568	absolute	: 24.4999		
environment	914.3843	fault in %:	2.3539	absolute	: 21.5234		
Results fit							
data: 141.PI	X, b534b41	l					
Sum of square)					
Number of ite	erations:	5					
epsilon		fault in %:		absolute			
object	735.3388	fault in %:	4.1007				
environment	918.7600	fault in %:	3.7013	absolute	: 34.0057		